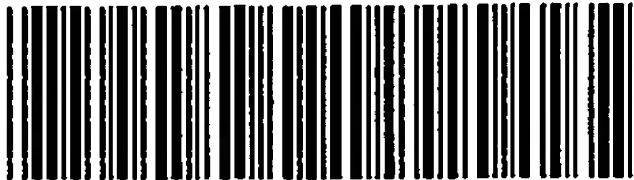


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/046,859	BOEHNKE ET AL.	
	Examiner	Art Unit	
	Hien Tran	1764	

SEARCHED			
Class	Subclass	Date	Examiner
422	177, 180, 179, 221, 222	11/18/2005	HT
60	299	11/18/2005	HT

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East Image class/subclass search / Inventors' names search / text search	11/18/2005	HT